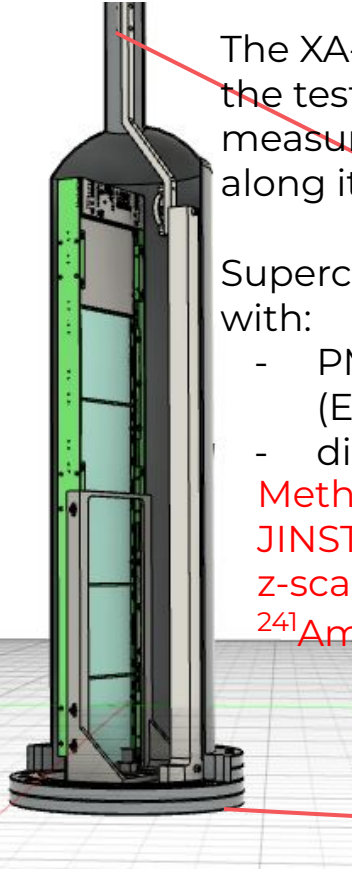
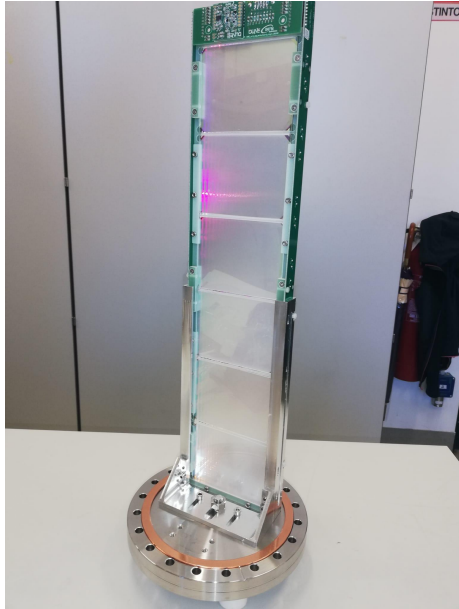


HD Supercell efficiency measurements in Liquid Argon @ Milano-Bicocca: updated results

C. Massari, on behalf of the MiB working group
25/10/2022

Setup to measure the XA-HD-SC PDE in LAr

The XA-HD-SC w. Cold FE circuit (top)

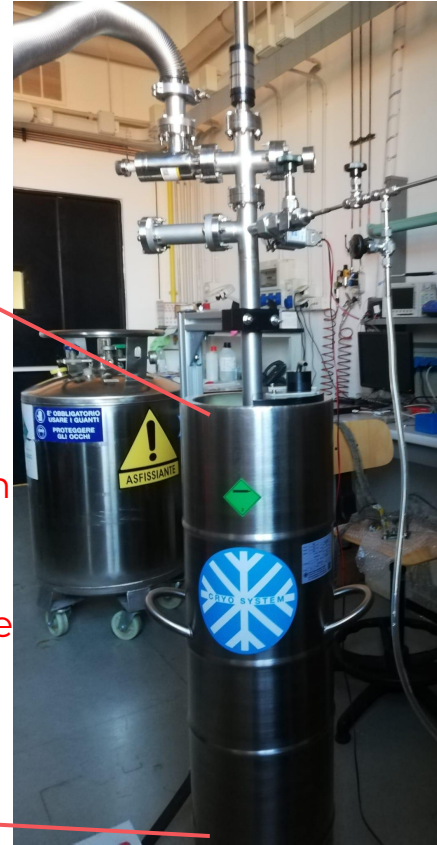


The XA-SC installed in the test chamber to measure the PDE along its z-axis.

Supercell equipped with:

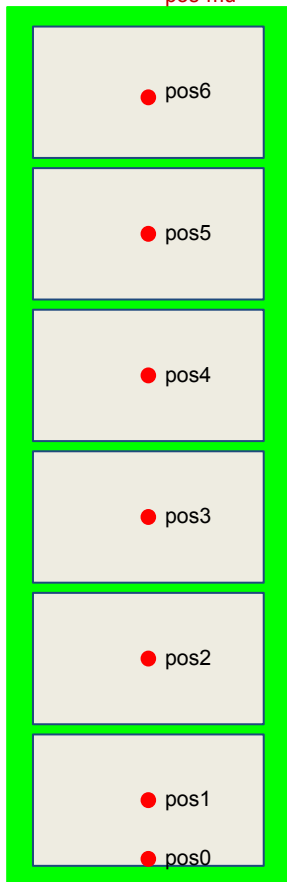
- PMMA WLS (ELJ&G2P)
- dichroic filters

Method as published in JINST 16 (2021) 09027:
z-scanning with an ^{241}Am exposed α source



Method & Data taking

pos-mu



z-scanning of the SC with the ^{241}Am α (5.480 MeV) source at the following positions:

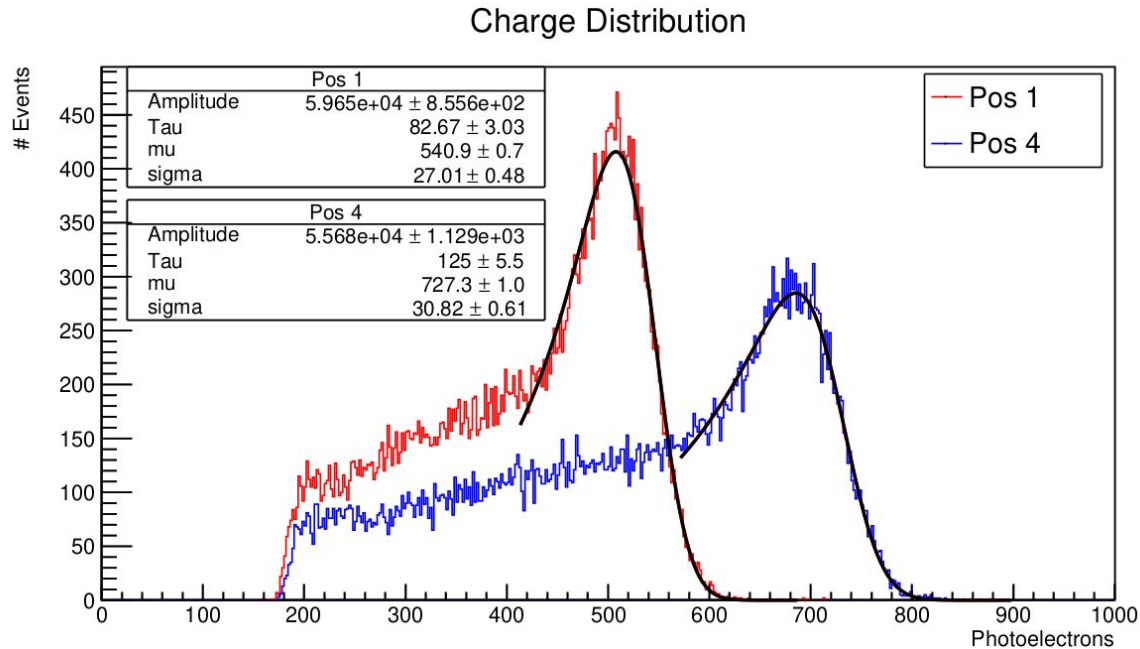
1. **pos0**: (the lowest possible): ~ 2 cm above the flange.
2. **pos1, 2, 3, 4, 5, 6**: the center of each dichroic filter.
Acquired: $10^4 \times 4$ wfms; 20 μs length; ~ 5 μs pretrigger.
3. Source at the topmost position (~ 49 cm from the flange) and \sim out of LAr:
 - one **μ run** ($10^4 \times 4$ events; 20 μs , 5 μs pretrigger)
 - one **s.p.h.e. run** ($10^4 \times 8$ events; 20 μs length; 1.6 μs pretrigger)

Source-to-dichroic filter distance: (55 +/- 1) mm.

What we updated

- Corrected the evaluation of the source position
- Improved evaluation of statistical errors
- New analysis of F_{int} and LAr purity correction using a new template
- Introduction of a systematic error for the non-uniformity of the PDE

Fit of alpha spectra: an example



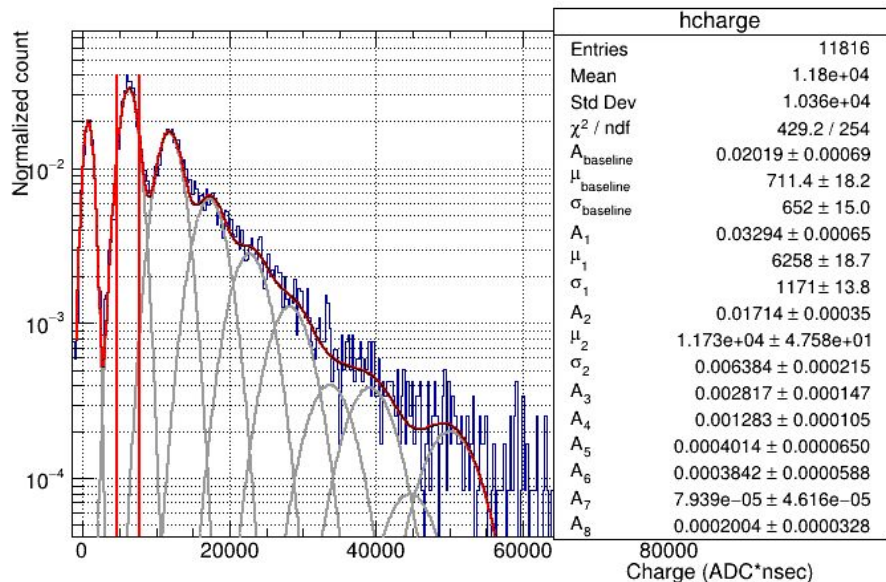
pos.1: $\sigma/\mu = 4.9 \%$

pos.4: $\sigma/\mu = 4.2 \%$

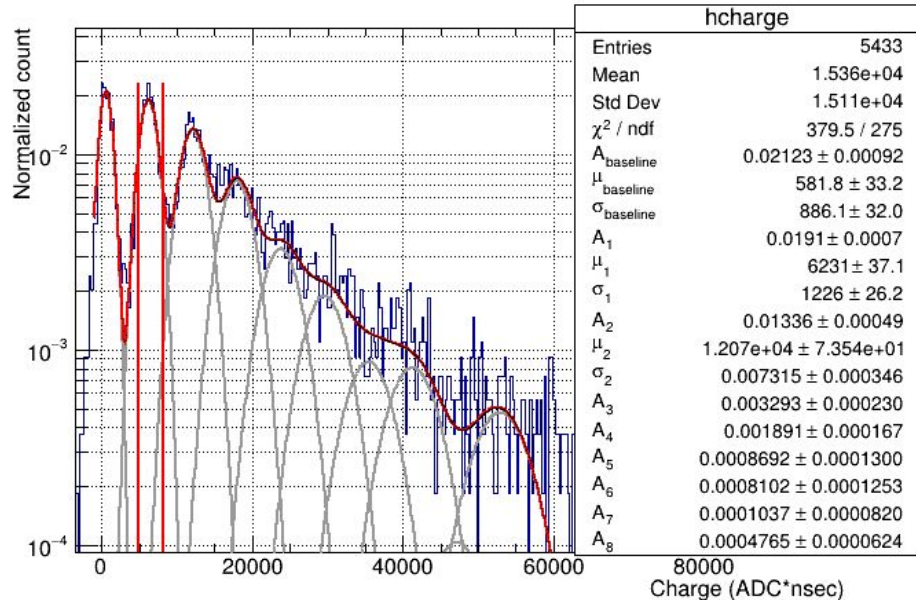
SC equipped with FBK & G2P

Single Photoelectrons spectrum

HPK S/N = 4.7



FBK S/N = 4.1



Solid angle evaluation

- Analytically computed as the solid angle of a pyramid with rectangular base (the SC):

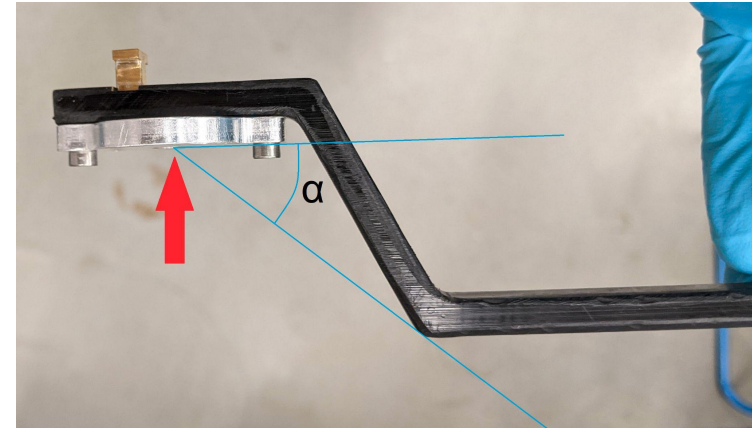
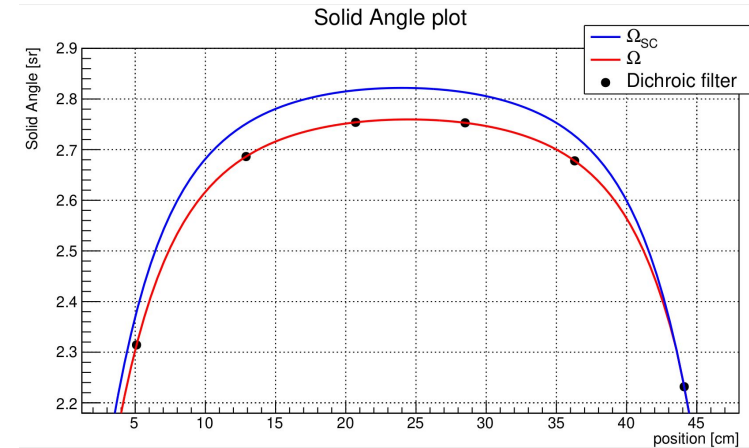
$$\Omega_{\text{SC}}(x) = 2 \arctan \left(\frac{abh}{2R_1(x^2 + h^2) + 2R_2[x(x-b) + h^2]} \right) + 2 \arctan \left(\frac{abh}{2R_1(x(x-b) + h^2) + 2R_2[(x-b)^2 + h^2]} \right)$$

- The plastic frame that holds the alpha source shadow a fraction of the solid angle:

$$\Omega_s(x) = 2 \arctan \left(\frac{wh(b-x-h \cot \alpha)}{2R_3[h \cot \alpha(b-x) + h^2] + 2R_4[(h \cot \alpha)^2 + h^2]} \right) + 2 \arctan \left(\frac{wh(b-x-h \cot \alpha)}{2R_3[(b-x)^2 + h^2] + 2R_4[h \cot \alpha(b-x) + h^2]} \right)$$

- The total solid angle is:

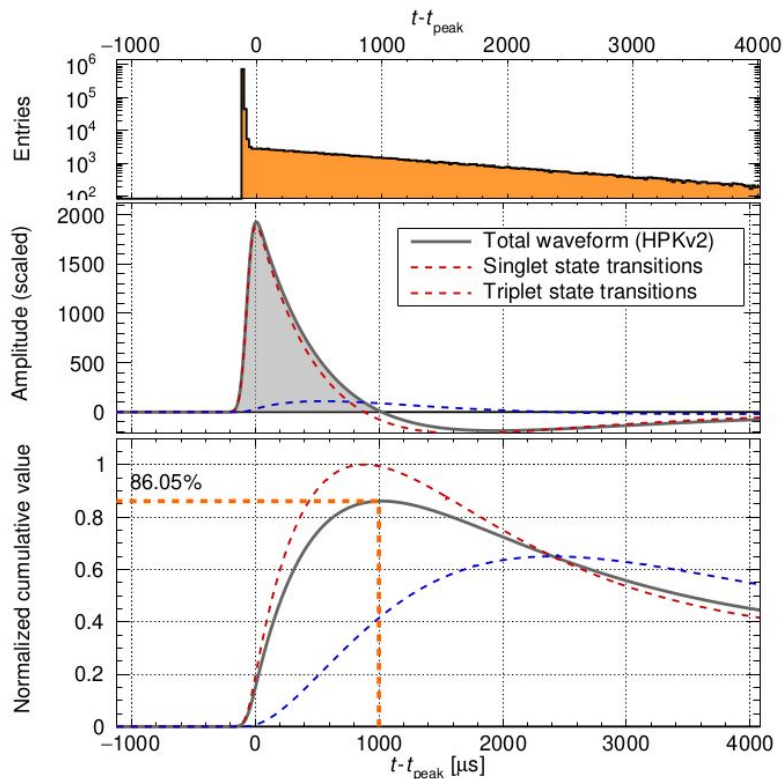
$$\Omega(x) = \begin{cases} \Omega_{\text{SC}}(x) - \Omega_s(x) & \text{if } x < b - h \cot \alpha \\ \Omega_{\text{SC}}(x) & \text{if } x \geq b - h \cot \alpha \end{cases}$$



Fraction of integrated light

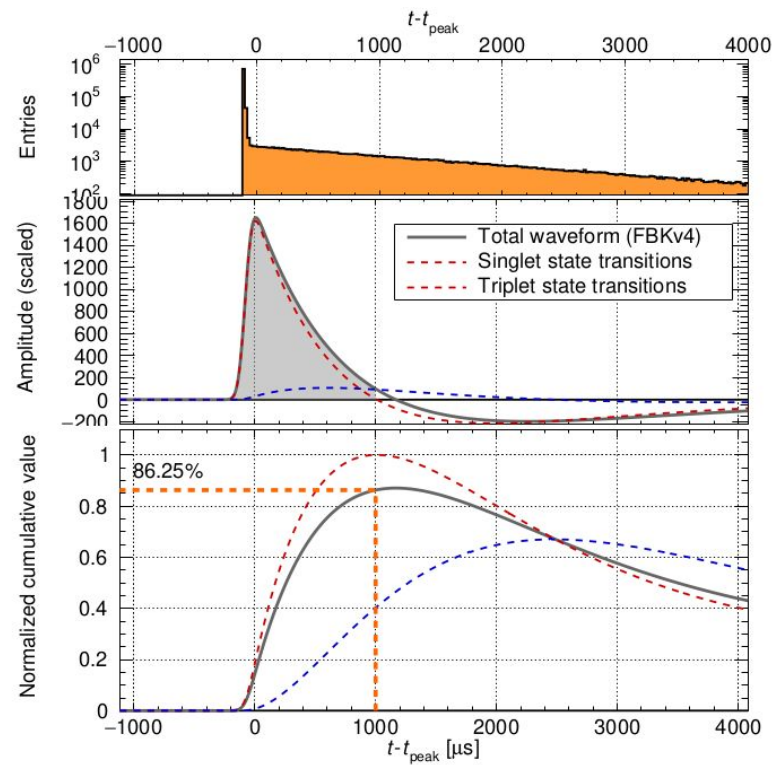
Synthetic wfms: SPHE \otimes LAr profile ($A_s=0.77$; $\tau_s=7\text{ns}$ $A_t=0.23$; $\tau_t=1400\text{ ns}$)

Fraction of Integrated light



HPK SPHE wfm

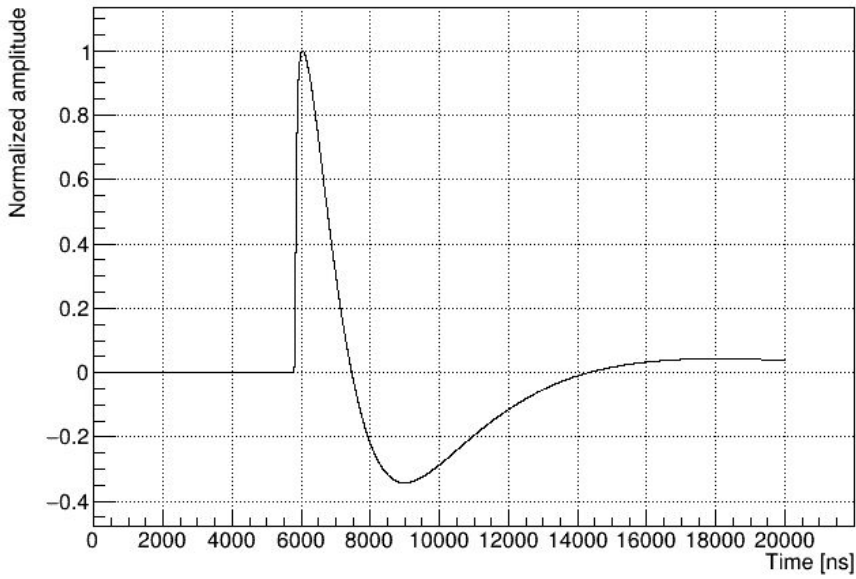
Fraction of Integrated light



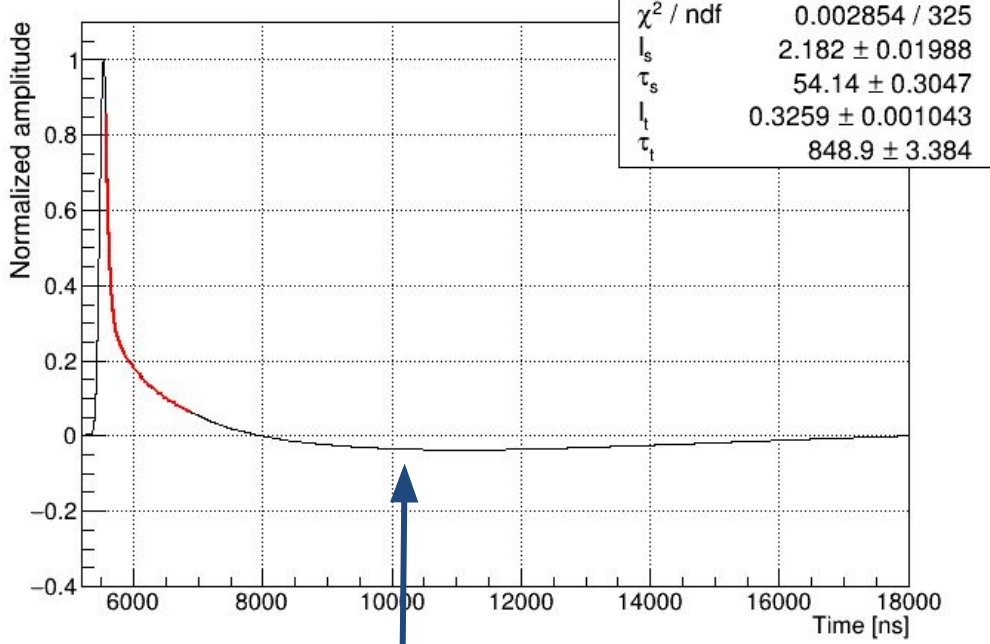
FBK SPHE wfm

Previous deconvoluted muon waveform

Average muon waveform with FBK



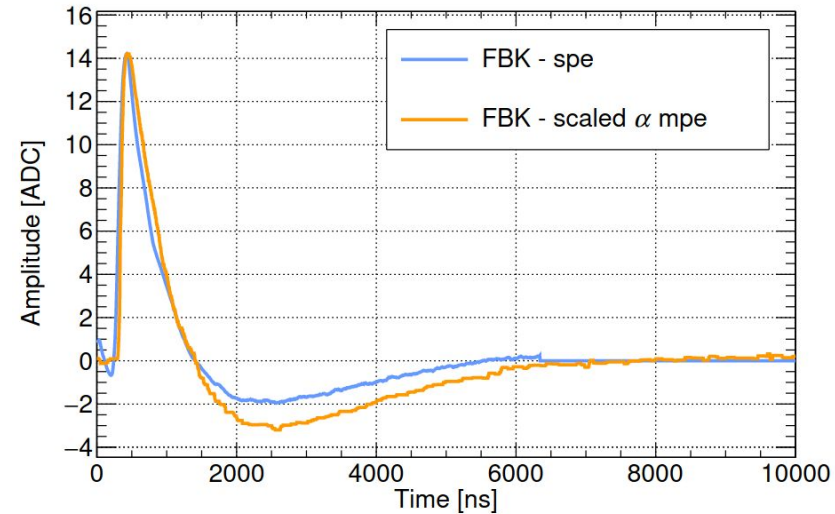
Deconvoluted muon waveform with FBK



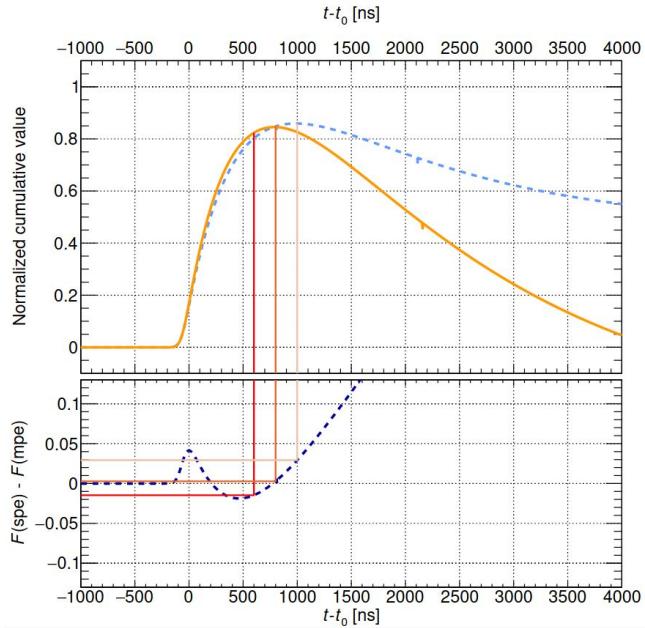
residual negative part

Multi-photoelectron template

- Since the deconvolution of the muon average waveform using the sphe mean waveform failed, we tried using a different “template”
- Selected an alpha event with few photoelectrons ($\sim 70pe$), with a high F_{prompt} ($F_{\text{prompt}} > 0.9$) and normalized its amplitude
- Used this new template for the determination of F_{int} and the LAr purity correction

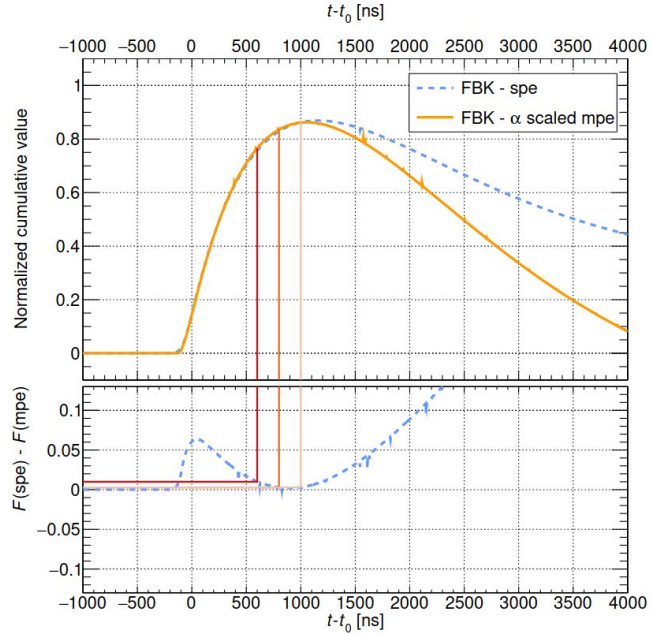


Mpe F_{int} evaluation



HPK

$\sim 3\%$ difference from spe template

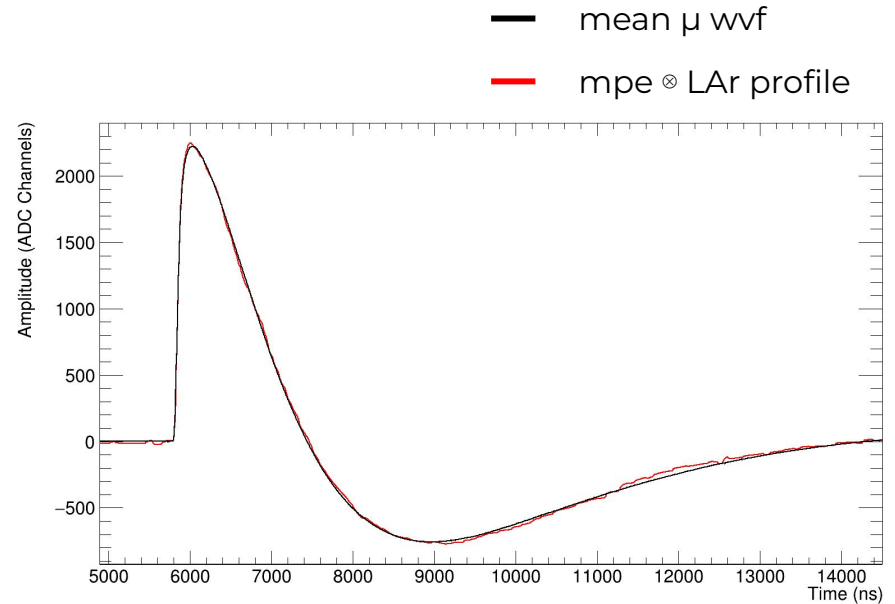


FBK

$< 1\%$ difference from spe template

Mpe muon convolution

- Convolution of the mpe template with LAr scintillation profile
- Fit the function with the average muon waveform and extract τ_T
- Achieved a good fit and a reliable value of τ_T
- We did it only for the FBK&G2P data

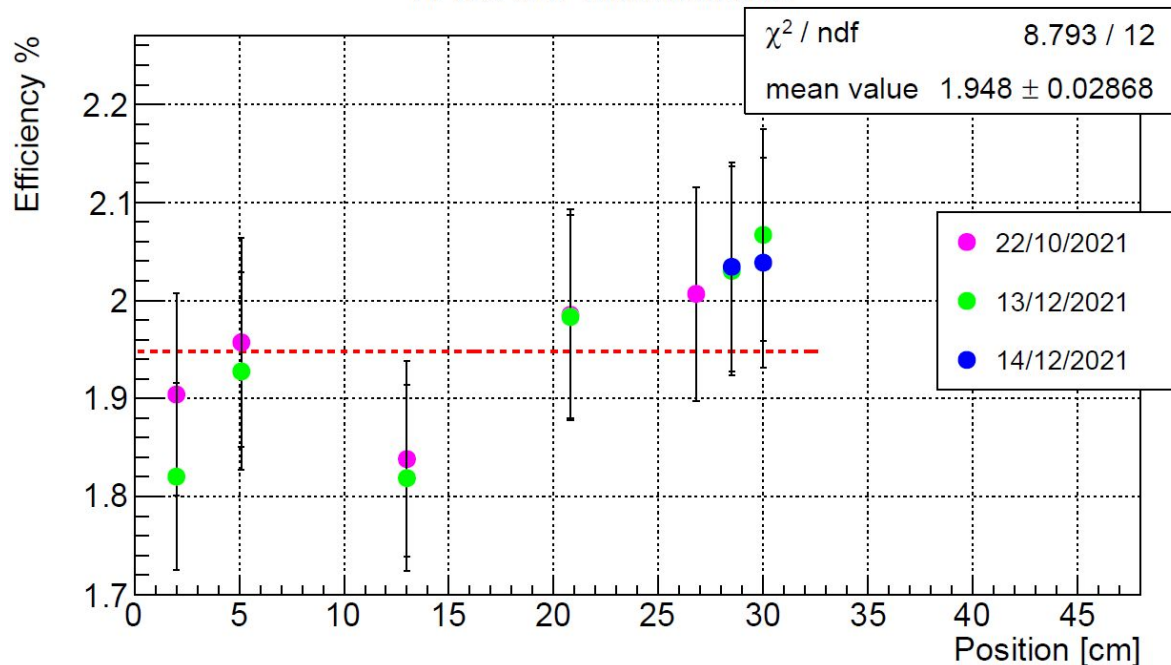


$$\tau_T = 1069 \text{ ns}$$

Efficiency results: HPK & G2P

$$\epsilon = \frac{4\pi \cdot \alpha \text{ peak(ADC)}}{\text{s.p.h.e.(ADC)} \cdot f_{int} \cdot LY_{LAr} \cdot En_{\alpha} \cdot q_{\alpha} \cdot \Omega}$$

HPK & G2P Measurements

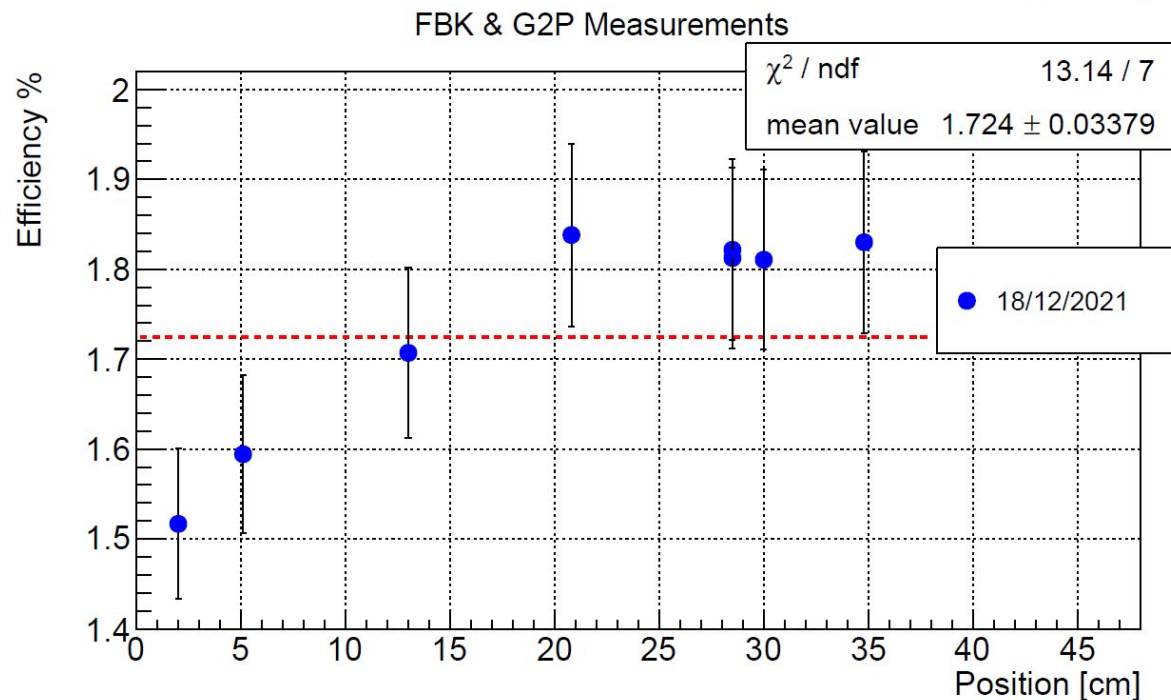


$LY_{LAr} = 5.0 \text{ E}+4$
 $q_{\alpha} = 0.7$
 $En_{\alpha} = 5.480 \text{ MeV}$
 $f_{int} = 0.862$

No X-talk and LAr
purity corrections

Efficiency results: FBK & G2P

$$\epsilon = \frac{4\pi \cdot \alpha \text{ peak(ADC)}}{\text{s.p.e.(ADC)} \cdot f_{int} \cdot LY_{LAr} \cdot En_{\alpha} \cdot q_{\alpha} \cdot \Omega}$$



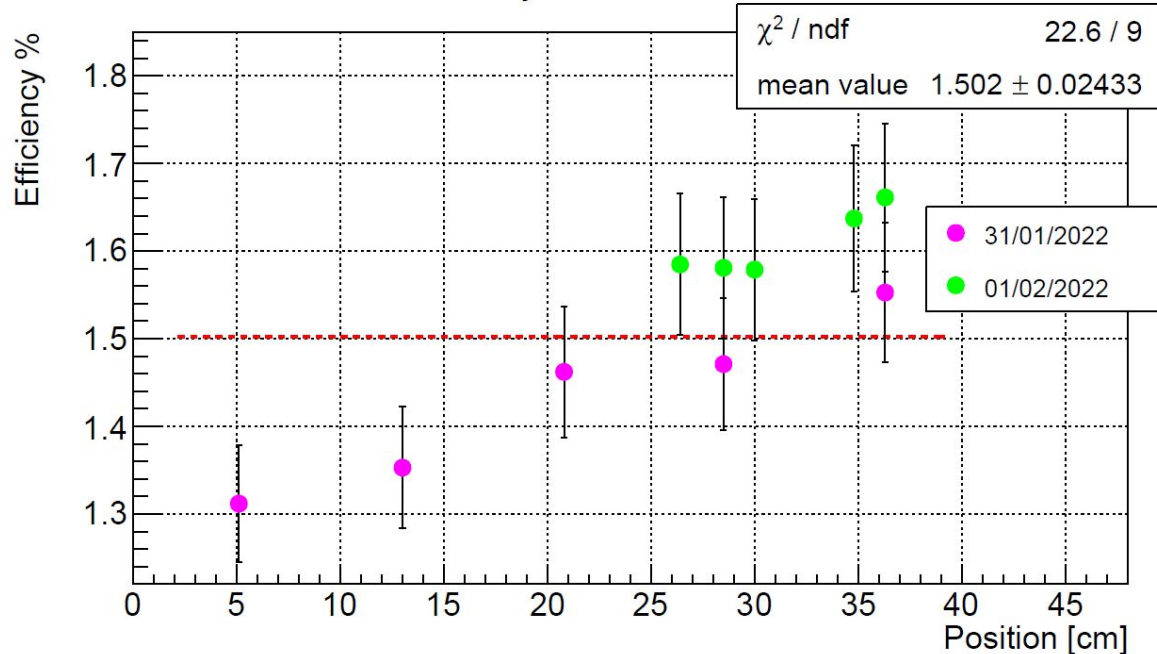
$LY_{LAr} = 5.0 \text{ E}+4$
 $q_{\alpha} = 0.7$
 $En_{\alpha} = 5.480 \text{ MeV}$
 $f_{int} = 0.86$

No X-talk and LAr
purity corrections

Efficiency results: FBK & Eljen

$$\epsilon = \frac{4\pi \cdot \alpha \text{ peak(ADC)}}{\text{s.ph.e.(ADC)} \cdot f_{int} \cdot LY_{\text{LAr}} \cdot E_{n\alpha} \cdot q_{\alpha} \cdot \Omega}$$

FBK & Eljen Measurements

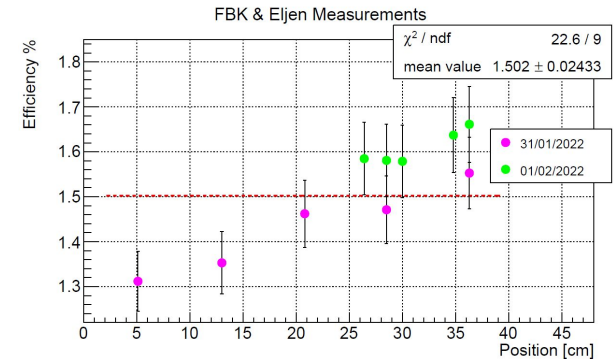
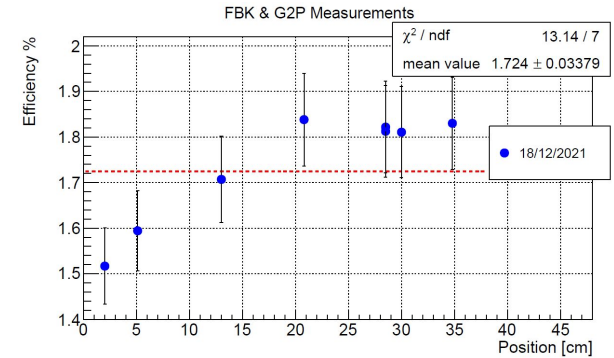


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 $f_{int} = 0.86$

No X-talk and LAr
purity corrections

Systematic uncertainty

- Lowest positions ($x < 15\text{cm}$) with FBK show a worse PDE
 - May be caused by one (or more) SiPM board with a higher V_{bkd} or by dichroic filters with worse performances in the lowest positions
 - Systematic error as the difference between the average PDE with all position ϵ_{all} and average PDE with higher positions ($x > 15\text{cm}$) ϵ_{c}



Efficiency: X-talk and P_{LAr} corrections

		OV	PDE	Uncorrected ϵ_{XA}	Measured Xtalk	P_{LAr}	Position systematic	Corrected ϵ_{XA} x talk only	Corrected ϵ_{XA} x talk and P_{LAr}
this work	HPK** & G2P	3.0V	50%	1.94 (0.03)	6.62%	TBD	0.08	1.82 (0.08)	
	FBK*** & G2P	4.5V	45%	1.72 (0.03)	15.7%	1.06	0.10	1.49 (0.10)	1.58 (0.10)
	FBK*** & Eljen	4.5V	45%	1.50 (0.02)	15.7%	TBD	0.06	1.29 (0.07)	
JINST work	HPK commercial*	2.7V	45%	3.5 (0.1)	22%			2.9 (0.1)	

* S14160-6050HS (6 × 6) mm², 50 μm

** 75um-HQR

*** Triple Trench

$$P_{LAr} = \left(0.77 + 0.23 \times \frac{\tau_T}{1414 \text{ ns}} \right)^{-1}$$

Conclusions

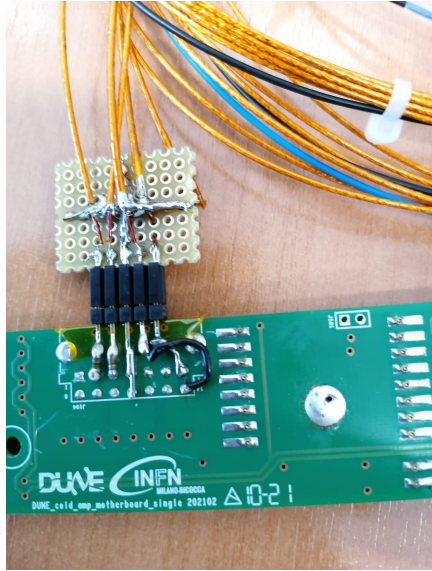
- A non-linearity of the system response affected the determination of τ_T
 - Using a new mpe template we achieved a reliable better estimation of τ_T and the LAr purity correction
 - We also re-computed F_{int} showing a significant difference in the HPK data
- We observed a non-uniformity in the PDE along the SC dimension
 - There are several effects that may cause a disuniformity in the SC PDE (different V_{bkd} , dichroic filters, gap between SiPMs and WLS bar...)
 - The “real” PDE of the SC average all those effects

Backup

Features of the XA HD Supercell under tests

Size/type of the WLS slab Dichoics (sipm/WLS) area	G2P 480 x 93 mm ² , NO Vikuiti on short edges 6 x dichroics (Opto-Campinas) 3.9%
SIPMs	HPK DUNE-75um-HQR, +3V OV (50% PDE) FBK TT, +4.5V OV (45% PDE)
Ganging	x 48 SiPMs by MiB cold Amplifier
# electronic channels	1
SiPMs -Cold Amp. Cold Amp dyn. range	AC 2000 ph.e.
s.ph.e. (50 Ω , 45 V)	~ 2.0 mV on 50 Ω for both HPK and FBK
Chamber volume	~ 10 l
Digitizer	CAEN 14-bit 250 MS/sec, 4 ns/sample

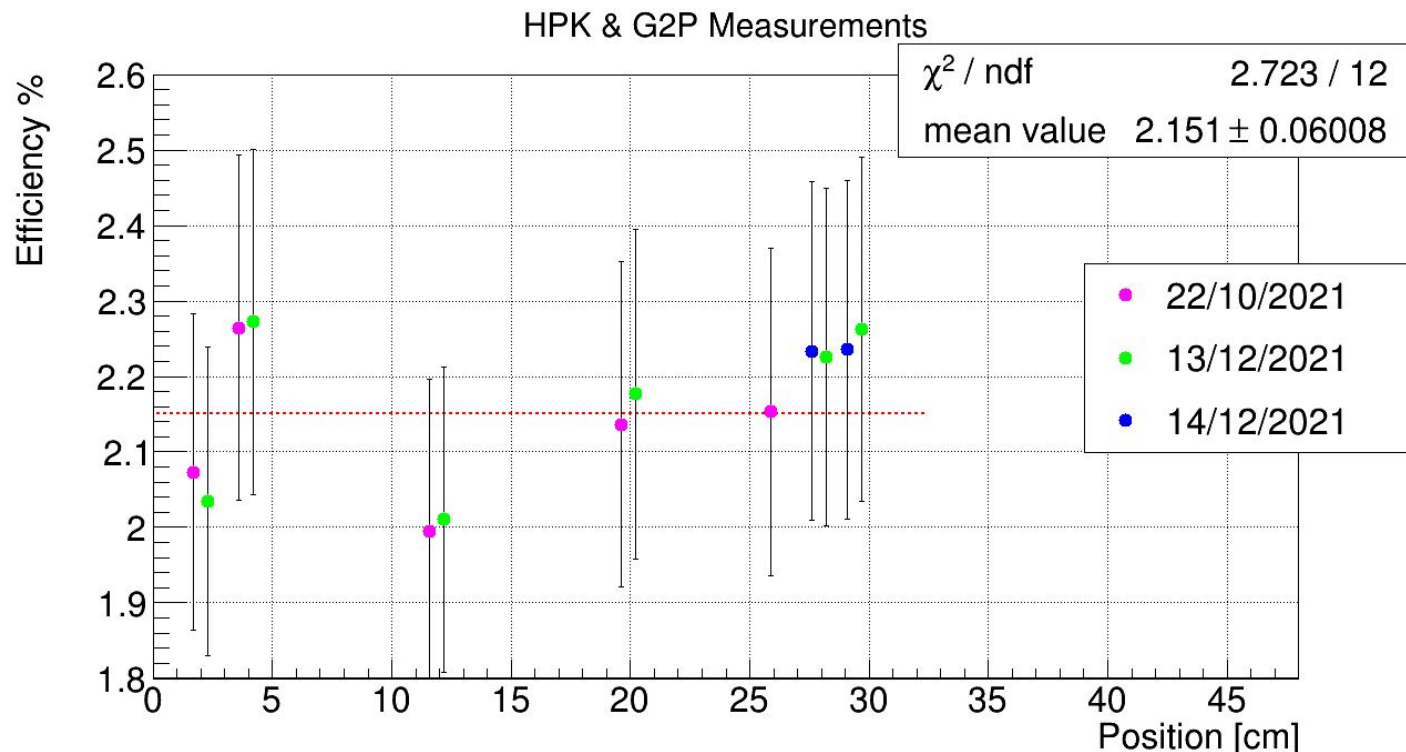
Hardware



- Cold cables: a bundle of five Kapton RG178 coaxial cables. No DUNE blue cable & Hirose connector due to mechanical (dimension, stiffness) constraints of the setup
- Warm cables: 2.5 m, 50 Ω LEMO cables
- Cold-to-warm flange: 10 contacts vacuum/pressure connector mounted on a CF40 flange - No Hirose:
 - **the chamber and its payload are pumped down to 10^{-4} mbar prior filling \rightarrow**
 - **high LAr purity achieved with high reproducibility**
 - **the purity is maintained w.o. any recirculation along several days from filling**

Efficiency: Updated results HPK & G2P

$$\epsilon = \frac{4\pi \cdot \alpha \text{ peak(ADC)}}{\text{s.p.h.e.(ADC)} \cdot f_{int} \cdot LY_{LAr} \cdot En_{\alpha} \cdot q_{\alpha} \cdot \Omega}$$

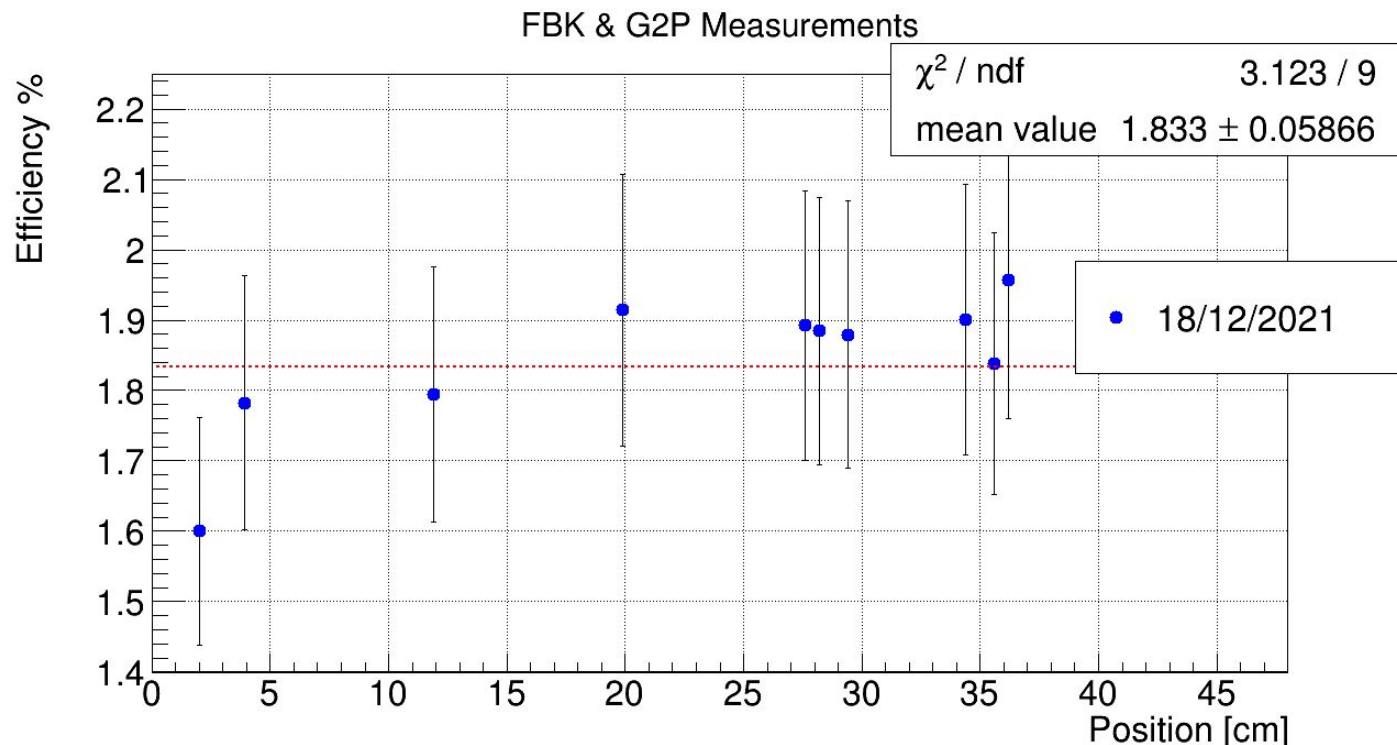


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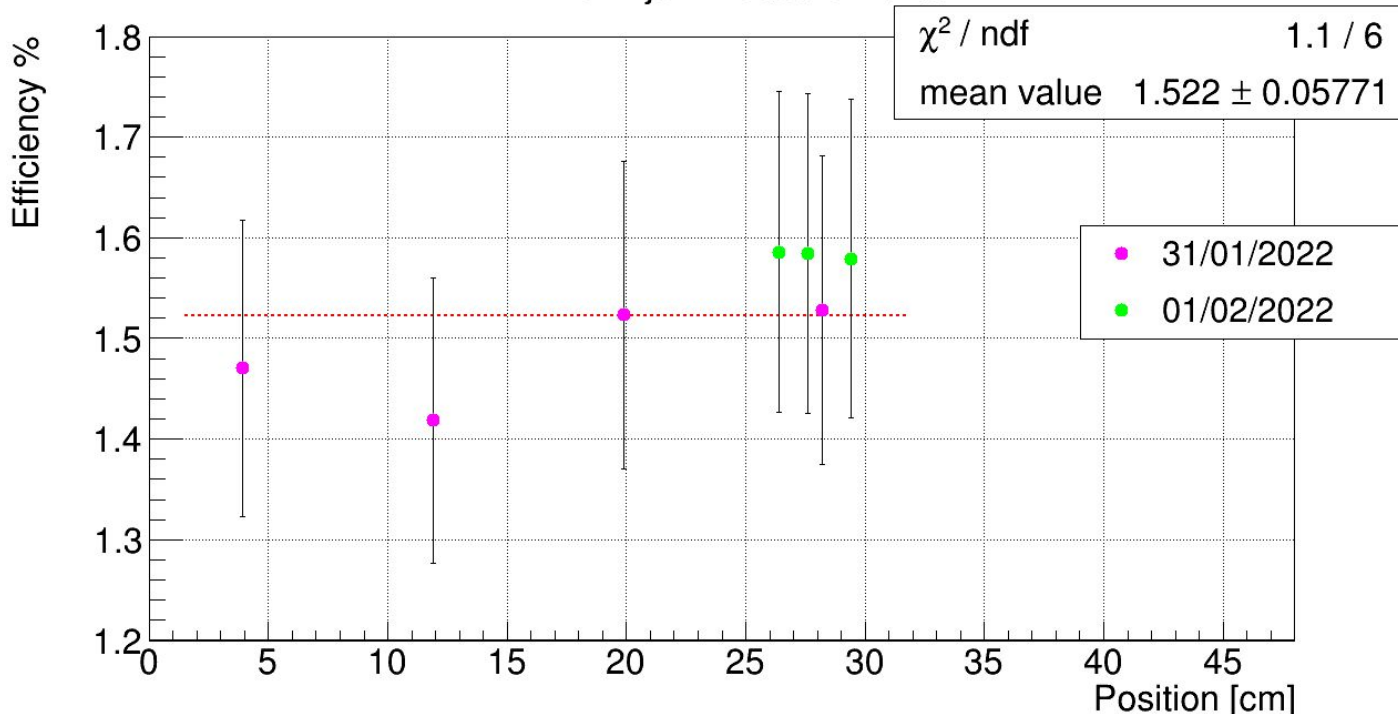
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Efficiency: Updated results

FBK & Eljen

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FBK & Eljen Measurements



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